

**Search Notes**

Application/Control No.

10/667,598

Examiner

Richard K. Lee

Applicant(s)/Patent under  
Reexamination

NAKAZAWA ET AL.

Art Unit

2832

**SEARCHED**

Class	Subclass	Date	Examiner
200	16R	1/24/2004	KL
	16A		
	549		
	550		
	275		
	252		
	280		
200	557	1/24/2004	KL
Search	updated.	3/16/2005	KL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Same as	above.	3/16/2005	KL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR